

April 2000

# **FQA38N30**

### 300V N-Channel MOSFET

### **General Description**

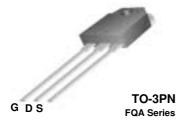
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

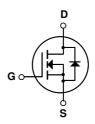
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply.

#### **Features**

- 38.4A, 300V, R<sub>DS(on)</sub> = 0.085Ω @V<sub>GS</sub> = 10 V
   Low gate charge (typical 90 nC)
   Low Crss (typical 70 pF)

- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQA38N30	Units	
V <sub>DSS</sub>	Drain-Source Voltage		300	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C	C)	38.4	Α	
	- Continuous (T <sub>C</sub> = 100°	°C)	24.3	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	153.6	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	1500	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	38.4	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	29	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		290	W	
	- Derate above 25°C		2.33	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.43	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	300			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.35		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 300 V, V <sub>GS</sub> = 0 V			1	μΑ
		V <sub>DS</sub> = 240 V, T <sub>C</sub> = 125°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 19.2 A		0.065	0.085	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 19.2 A (Note 4)		24		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		3380 670 70	4400 870 90	pF pF pF
Cwitab	ing Characteristics	1				
t <sub>d(on)</sub>	Ing Characteristics Turn-On Delay Time			80	170	ns
t <sub>r</sub>	Turn-On Rise Time	V <sub>DD</sub> = 150 V, I <sub>D</sub> = 38.4 A,		430	870	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25 \Omega$		170	350	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		190	390	ns
$Q_q$	Total Gate Charge	V <sub>DS</sub> = 240 V, I <sub>D</sub> = 38.4 A,		90	120	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 240 V, I <sub>D</sub> = 30.4 A, V <sub>GS</sub> = 10 V		23		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		44		nC
Drain S	Source Diede Characteristics a	nd Maximum Patings	•			
Draini-S	Source Diode Characteristics and Maximum Ratings  Maximum Continuous Drain-Source Diode Forward Current				38.4	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				153.6	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 38.4 A			1.5	V
- 30						
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 38.4 A,		300		ns

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.7mH, I<sub>AS</sub> = 38.4A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  38.4A, di/dt  $\leq$  200A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

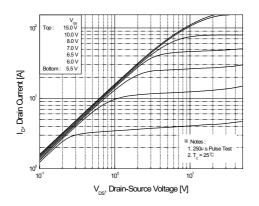


Figure 1. On-Region Characteristics

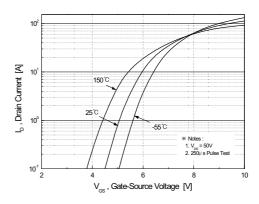


Figure 2. Transfer Characteristics

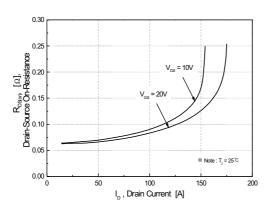


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

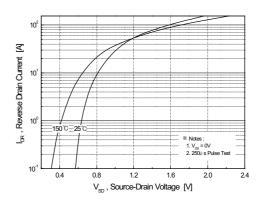


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

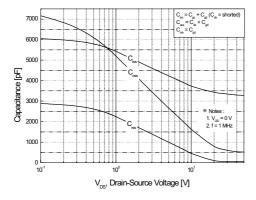


Figure 5. Capacitance Characteristics

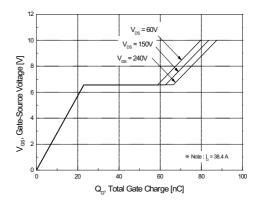
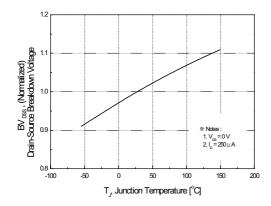


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



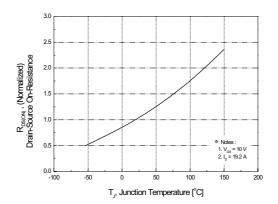
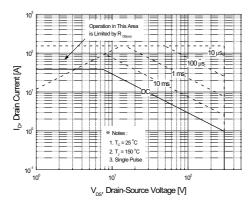


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



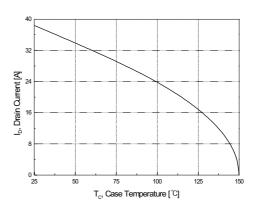


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

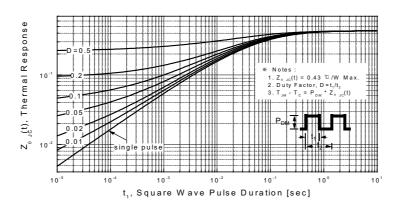
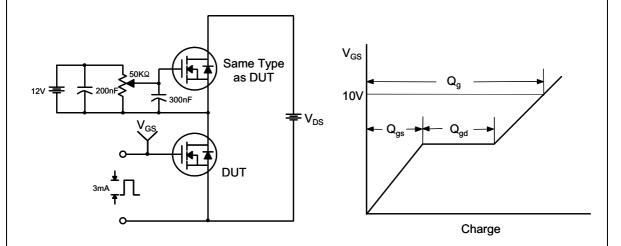


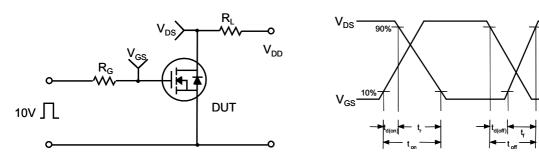
Figure 11. Transient Thermal Response Curve

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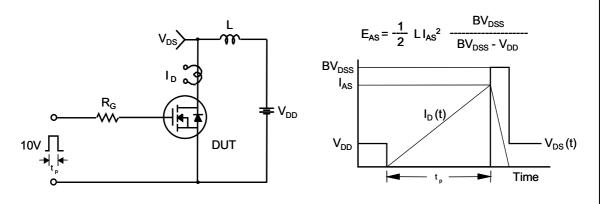
## **Gate Charge Test Circuit & Waveform**



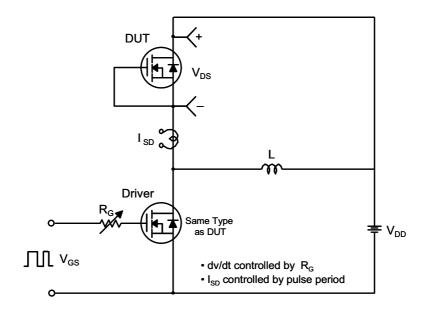
## **Resistive Switching Test Circuit & Waveforms**

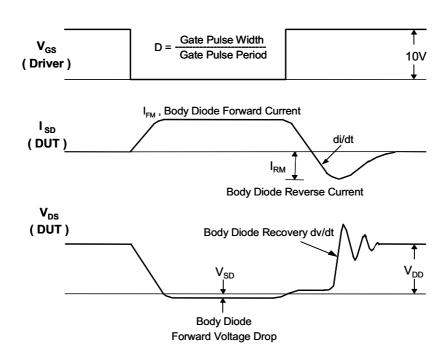


## **Unclamped Inductive Switching Test Circuit & Waveforms**



### Peak Diode Recovery dv/dt Test Circuit & Waveforms

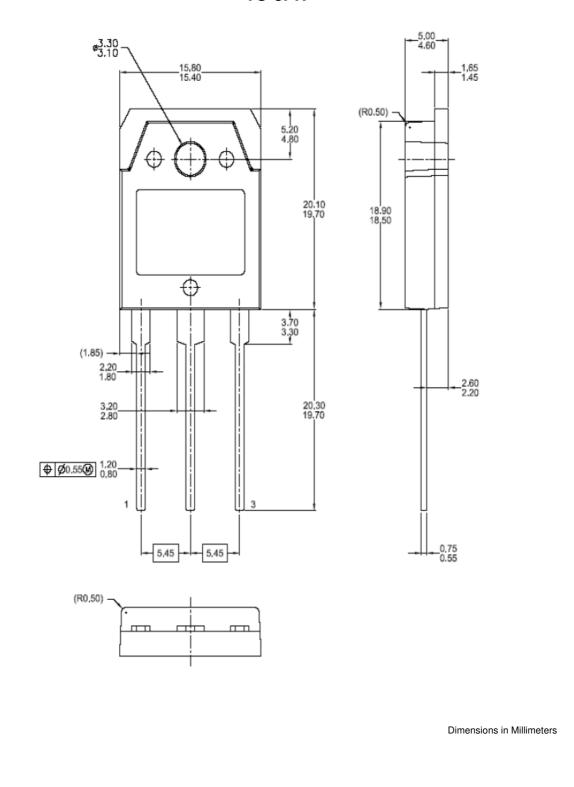




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# **Mechanical Dimensions**

# TO-3PN



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